NTB0102-Q100

Dual supply translating transceiver; auto direction sensing; 3-state

Rev. 2.0 — 20 April 2022

Product data sheet

1 General description

The NTB0102-Q100 is a 2-bit, dual supply translating transceiver with auto direction sensing, that enables bidirectional voltage level translation. It features two 2-bit input-output ports (An and Bn), one output enable input (OE) and two supply pins ($V_{CC(A)}$ and $V_{CC(B)}$). $V_{CC(A)}$ can be supplied with any voltage between 1.2 V and 3.6 V and $V_{CC(B)}$ can be supplied with any voltage between 1.65 V and 5.5 V. This flexibility makes the device suitable for translating between any of the low voltage nodes (1.2 V, 1.5 V, 1.8 V, 2.5 V, 3.3 V and 5.0 V).

Pins An and OE are referenced to $V_{CC(A)}$ and pins Bn are referenced to $V_{CC(B)}$. A LOW level at pin OE causes the outputs to assume a high-impedance OFF-state. This device is fully specified for partial power-down applications using I_{OFF} . The I_{OFF} circuitry disables the output, preventing the damaging backflow current through the device when it is powered down.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2 Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
 - Specified from -40 °C to +85 °C and from -40 °C to +125 °C
- Wide supply voltage range:
 - V_{CC(A)}: 1.2 V to 3.6 V and V_{CC(B)}: 1.65 V to 5.5 V
- I_{OFF} circuitry provides partial Power-down mode operation
- Inputs accept voltages up to 5.5 V
- ESD protection:
 - MIL-STD-883, method 3015 Class 2 exceeds 2500 V for A port
 - MIL-STD-883, method 3015 Class 3B exceeds 15000 V for B port
 - HBM JESD22-A114E Class 2 exceeds 2500 V for A port
 - HBM JESD22-A114E Class 3B exceeds 15000 V for B port
- Latch-up performance exceeds 100 mA per JESD 78B Class II
- · Multiple package options

3 Ordering information

Table 1. Ordering information

Type number	Topside	Package		
	marking	Name	Description	Version
NTB0102DP-Q100	t02	TSSOP8	plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm	SOT505-2



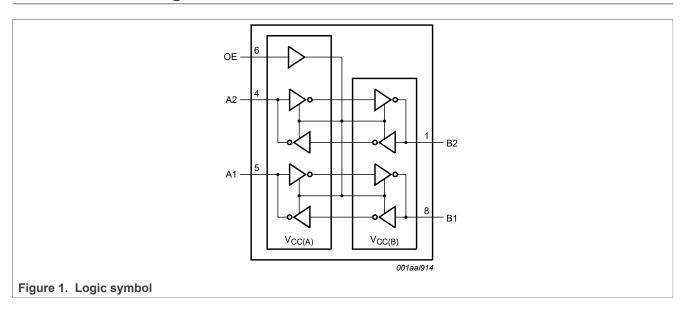
3.1 Ordering options

Table 2. Ordering options

Type number	Orderable part number	Package	Packing method [1]	Minimum order quantity	Temperature
NTB0102DP-Q100	NTB0102DP-Q100H	TSSOP8	REEL 7" Q3 NDP	3000	-40 °C to +125 °C

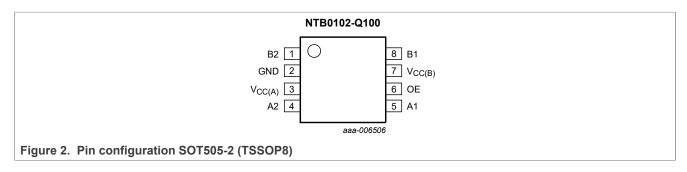
^[1] Standard packing quantities and other packaging data are available at www.nxp.com/packages/.

4 Functional diagram



5 Pinning information

5.1 Pinning



5.2 Pin description

Table 3. Pin description

14610 0. 1 111 40	Comption	
Symbol	Pin	Description
B2, B1	1, 8	data input or output (referenced to V _{CC(B)})
GND	2	ground (0 V)

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Table 3. Pin description...continued

Symbol	Pin	Description
V _{CC(A)}	3	supply voltage A
A2, A1	4, 5	data input or output (referenced to V _{CC(A)})
OE	6	output enable input (active HIGH; referenced to V _{CC(A)})
V _{CC(B)}	7	supply voltage B

Functional description

Table 4. Function table^[1]

Supply voltage		Input	Input/output	
V _{CC(A)} V _{CC(B)}		OE	An	Bn
1.2 V to V _{CC(B)}	1.65 V to 5.5 V	L	Z	Z
1.2 V to V _{CC(B)}	1.65 V to 5.5 V	Н	input or output	output or input
GND ^[2]	GND ^[2]	X	Z	Z

 $[\]label{eq:Hamiltonian} H = HIGH \ voltage \ level; \ L = LOW \ voltage \ level; \ X = don't \ care; \ Z = high-impedance \ OFF-state.$ When either $V_{CC(A)}$ or $V_{CC(B)}$ is at GND level, the device goes into Power-down mode.

Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{CC(A)}	supply voltage A			-0.5	+6.5	V
V _{CC(B)}	supply voltage B			-0.5	+6.5	V
VI	input voltage		[1]	-0.5	+6.5	V
Vo	output voltage	Active mode	[1][2][3]	-0.5	V _{CCO} + 0.5	V
		Power-down or 3-state mode	[1]	-0.5	+6.5	V
I _{IK}	input clamping current	V _I < 0 V		-50	-	mA
I _{OK}	output clamping current	V _O < 0 V		-50	-	mA
Io	output current	V _O = 0 V to V _{CCO}	[2]	-	±50	mA
I _{CC}	supply current	I _{CC(A)} or I _{CC(B)}		-	100	mA
I _{GND}	ground current			-100	-	mA
T _{stg}	storage temperature			-65	+150	°C
P _{tot}	total power dissipation	T _{amb} = -40 °C to +125 °C	[4]	-	250	mW

The minimum input and minimum output voltage ratings may be exceeded if the input and output current ratings are observed.

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 $V_{\mbox{\footnotesize{CCO}}}$ is the supply voltage associated with the output.

V_{CCO} + 0.5 V should not exceed 6.5 V.

For TSSOP8 package: above 55 °C the value of Ptot derates linearly with 2.5 mW/K.

8 Recommended operating conditions

Table 6. Recommended operating conditions^{[1][2]}

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC(A)}	supply voltage A		1.2	3.6	V
V _{CC(B)}	supply voltage B		1.65	5.5	V
VI	input voltage		0	5.5	V
Vo	output voltage	Power-down or 3-state mode; V _{CC(A)} = 1.2 V to 3.6 V; V _{CC(B)} = 1.65 V to 5.5 V			
		A port	0	3.6	V
		B port	0	5.5	V
T _{amb}	ambient temperature		-40	+125	°C
Δt/ΔV	input transition rise and fall rate	V _{CC(A)} = 1.2 V to 3.6 V; V _{CC(B)} = 1.65 V to 5.5 V	-	40	ns/V

^[1] The A and B sides of an unused I/O pair must be held in the same state, both at V_{CCI} or both at GND.

9 Static characteristics

Table 7. Typical static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); T_{amb} = 25 °C.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{OH}	HIGH-level output voltage	A port; $V_{CC(A)} = 1.2 \text{ V}$; $I_O = -20 \mu\text{A}$		-	1.1	-	V
V _{OL}	LOW-level output voltage	A port; $V_{CC(A)} = 1.2 \text{ V}$; $I_O = 20 \mu\text{A}$		-	0.09	-	V
lı	input leakage current	OE input; V_I = 0 V to 3.6 V; $V_{CC(A)}$ = 1.2 V to 3.6 V; $V_{CC(B)}$ = 1.65 V to 5.5 V		-	-	±1	μA
I _{OZ}	OFF-state output current	A or B port; $V_O = 0 \text{ V to } V_{CC(A)}$; $V_{CC(A)} = 1.2 \text{ V to } 3.6 \text{ V}$; $V_{CC(B)} = 1.65 \text{ V to } 5.5 \text{ V}$	[1]	-	-	±1	μA
I _{OFF}	power-off leakage current	A port; V_1 or V_0 = 0 V to 3.6 V; $V_{CC(A)}$ = 0 V; $V_{CC(B)}$ = 0 V to 5.5 V		-	-	±1	μA
		B port; V_1 or V_0 = 0 V to 5.5 V; $V_{CC(B)}$ = 0 V; $V_{CC(A)}$ = 0 V to 3.6 V		-	-	±1	μA
I _{CC}	supply current	$V_I = 0 \text{ V or } V_{CCI}; I_O = 0 \text{ A}$	[2]				
		I _{CC(A)} ; V _{CC(A)} = 1.2 V; V _{CC(B)} = 1.65 V to 5.5 V		-	0.05	-	μA
		I _{CC(B)} ; V _{CC(A)} = 1.2 V; V _{CC(B)} = 1.65 V to 5.5 V		-	3.3	-	μA
		I _{CC(A)} + I _{CC(B)} ; V _{CC(A)} = 1.2 V; V _{CC(B)} = 1.65 V to 5.5 V		-	3.5	-	μA
C _I	input capacitance	OE input; $V_{CC(A)} = 1.2 \text{ V to } 3.6 \text{ V}; V_{CC(B)} = 1.65 \text{ V to } 5.5 \text{ V}$		-	1.0	-	pF
C _{I/O}	input/output	A port; V _{CC(A)} = 1.2 V to 3.6 V; V _{CC(B)} = 1.65 V to 5.5 V		-	4.0	-	pF
	capacitance	B port; V _{CC(A)} = 1.2 V to 3.6 V; V _{CC(B)} = 1.65 V to 5.5 V		-	7.5	-	pF

^[2] $V_{CC(A)}$ must be less than or equal to $V_{CC(B)}$.

- V_{CCO} is the supply voltage associated with the output. V_{CCI} is the supply voltage associated with the input.

Table 8. Typical supply current

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); T_{amb} = 25 °C.

V _{CC(A)}				V _C	C(B)				Unit
	1.8	8 V	2.	5 V	3.3	3 V	5.0) V	
	I _{CC(A)}	I _{CC(B)}	nA nA						
1.2 V	10	10	10	10	10	20	10	1050	nA
1.5 V	10	10	10	10	10	10	10	650	nA
1.8 V	10	10	10	10	10	10	10	350	nA
2.5 V	-	-	10	10	10	10	10	40	nA
3.3 V	-	-	-	-	10	10	10	10	nA

Table 9. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		-40 °C to	+85 °C	-40 °C to	+125 °C	Unit
				Min	Max	Min	Max	
V _{IH}	HIGH-level	A or B port and OE input	[1]					
	input voltage	V _{CC(A)} = 1.2 V to 3.6 V; V _{CC(B)} = 1.65 V to 5.5 V		0.65V _{CCI}	-	0.65V _{CCI}	-	V
V _{IL}	LOW-level	A or B port and OE input	[1]					
	input voltage	V _{CC(A)} = 1.2 V to 3.6 V; V _{CC(B)} = 1.65 V to 5.5 V		-	0.35V _{CCI}	-	0.35V _{CCI}	V
V _{OH}	HIGH-level	Ι _O = -20 μΑ	[2]					
output voltage	A port; V _{CC(A)} = 1.4 V to 3.6 V		V _{CCO} - 0.4	-	V _{CCO} - 0.4	-	V	
		B port; V _{CC(B)} = 1.65 V to 5.5 V		V _{CCO} - 0.4	-	V _{CCO} - 0.4	-	V
V _{OL}	LOW-level	Ι _O = 20 μΑ	[2]					
	output voltage	A port; V _{CC(A)} = 1.4 V to 3.6 V		-	0.4	-	0.4	V
		B port; V _{CC(B)} = 1.65 V to 5.5 V		-	0.4	-	0.4	V
I _I	input leakage current	OE input; $V_I = 0 \text{ V to } 3.6 \text{ V}$; $V_{CC(A)} = 1.2 \text{ V to } 3.6 \text{ V}$; $V_{CC(B)} = 1.65 \text{ V to } 5.5 \text{ V}$		-	±2	-	±5	μA
l _{OZ}	OFF-state output current	A or B port; V _O = 0 V or V _{CCO} ; V _{CC(A)} = 1.2 V to 3.6 V; V _{CC(B)} = 1.65 V to 5.5 V	[2]	-	±2	-	±10	μA
l _{OFF}	power-off leakage	A port; V ₁ or V _O = 0 V to 3.6 V; V _{CC(A)} = 0 V; V _{CC(B)} = 0 V to 5.5 V		-	±2	-	±10	μΑ
	current	B port; V ₁ or V _O = 0 V to 5.5 V; V _{CC(B)} = 0 V; V _{CC(A)} = 0 V to 3.6 V		-	±2	-	±10	μΑ
I _{CC}	supply current	$V_I = 0 \text{ V or } V_{CCI}; I_O = 0 \text{ A}$	[1]					

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Table 9. Static characteristics...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C t	o +85 °C	-40 °C to	+125 °C	Unit
			Min	Max	Min	Max	
		I _{CC(A)}					
		OE = LOW; $V_{CC(A)}$ = 1.4 V to 3.6 V; $V_{CC(B)}$ = 1.65 V to 5.5 V	-	3	-	15	μΑ
		OE = HIGH; $V_{CC(A)}$ = 1.4 V to 3.6 V; $V_{CC(B)}$ = 1.65 V to 5.5 V	-	3	-	20	μΑ
		V _{CC(A)} = 3.6 V; V _{CC(B)} = 0 V	-	2	-	15	μΑ
		V _{CC(A)} = 0 V; V _{CC(B)} = 5.5 V	-	-2	-	-15	μΑ
		I _{CC(B)}					
		OE = LOW; $V_{CC(A)}$ = 1.4 V to 3.6 V; $V_{CC(B)}$ = 1.65 V to 5.5 V	-	5	-	15	μΑ
		OE = HIGH; $V_{CC(A)}$ = 1.4 V to 3.6 V; $V_{CC(B)}$ = 1.65 V to 5.5 V	-	5	-	20	μΑ
		V _{CC(A)} = 3.6 V; V _{CC(B)} = 0 V	-	-2	-	-15	μΑ
		V _{CC(A)} = 0 V; V _{CC(B)} = 5.5 V	-	2	-	15	μΑ
		I _{CC(A)} + I _{CC(B)}					
		V _{CC(A)} = 1.4 V to 3.6 V; V _{CC(B)} = 1.65 V to 5.5 V	-	8	-	40	μΑ

10 Dynamic characteristics

Table 10. Typical dynamic characteristics for temperature 25 ${}^{\circ}C^{[1]}$ Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 5; for waveforms see Figure 3 and Figure 4.

Symbol	Parameter	Conditions			V _C	C(B)		ns ns ps ns ns ns ns ns ns ns
				1.8 V	2.5 V	3.3 V	5.0 V	
V _{CC(A)} =	1.2 V; T _{amb} = 25 °C							
t _{pd}	propagation delay	A to B		5.9	4.8	4.4	4.2	ns
<u> </u>		B to A		5.6	4.8	4.5	4.4	ns
t _{en}	enable time	OE to A, B		0.5	0.5	0.5	0.5	μs
t _{dis}	disable time	OE to A; no external load	[2]	6.9	6.9	6.9	6.9	ns
		OE to B; no external load	[2]	9.5	8.6	8.5	8.0	ns ns
		OE to A		81	69	83	68	ns
		OE to B		81	69	83	68	ns
t _t	transition time	A port		4.0	4.0	4.1	4.1	ns
		B port		2.6	2.0	1.7	1.4	ns
t _{sk(o)}	output skew time	between channels	[3]	0.2	0.2	0.2	0.2	ns

 V_{CCI} is the supply voltage associated with the input. V_{CCO} is the supply voltage associated with the output.

Table 10. Typical dynamic characteristics for temperature 25 °C^[1]...continued Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 5; for waveforms see Figure 3 and Figure 4.

Symbol	Parameter	Conditions		V _{CC(B)}						
				1.8 V	2.5 V	3.3 V	5.0 V			
t _W	pulse width	data inputs		15	13	13	13	ns		
f _{data}	data rate			70	80	80	80	Mbps		

 t_{pd} is the same as t_{PLH} and t_{PHL} ; t_{en} is the same as t_{PZL} and t_{PZH} ; t_{dis} is the same as t_{PLZ} and t_{PHZ} ; t_{t} is the same as t_{THL} and t_{TLH} Delay between OE going LOW and when the outputs are actually disabled.

Table 11. Dynamic characteristics for temperature range -40 °C to +85 °C^[1] Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 5; for wave forms see Figure 3 and Figure 4.

Symbol	Parameter	Conditions					Vcc	C(B)				Unit
				1.8 V ±	0.15 V		5 V .2 V	3.3 V	± 0.3 V	5.0 V	± 0.5 V	
				Min	Max	Min	Max	Min	Max	Min	Max	-
V _{CC(A)} =	1.5 V ± 0.1 V											,
t _{pd}	propagation	A to B		1.4	12.9	1.2	10.1	1.1	10.0	0.8	9.9	ns
	delay	B to A		0.9	14.2	0.7	12.0	0.4	11.7	0.3	13.7	ns
t _{en}	enable time	OE to A, B		-	1.0	-	1.0	-	1.0	-	1.0	μs
t _{dis}	disable time	OE to A; no external load	[2]	1.0	11.9	1.0	11.9	1.0	11.9	1.0	11.9	ns
		OE to B; no external load	[2]	1.0	16.9	1.0	15.2	1.0	14.1	1.0	13.8	ns
		OE to A		-	320	-	260	-	260	-	280	ns
		OE to B		-	200	-	200	-	200	-	200	ns
t _t	transition	A port		0.9	5.1	0.9	5.1	0.9	5.1	0.9	5.1	ns
	time	B port		0.9	4.7	0.6	3.2	0.5	2.5	0.4	2.7	ns
t _{sk(o)}	output skew time	between channels	[3]	-	0.5	-	0.5	-	0.5	-	0.5	ns
t _W	pulse width	data inputs		25	-	25	-	25	-	25	-	ns
f _{data}	data rate			-	40	-	40	-	40	-	40	Mbps
V _{CC(A)} =	1.8 V ± 0.15 V											
t _{pd}	propagation	A to B		1.6	11.0	1.4	7.7	1.3	6.8	1.2	6.5	ns
	delay	B to A		1.5	12.0	1.3	8.4	1.0	7.6	0.9	7.1	ns
t _{en}	enable time	OE to A, B		-	1.0	-	1.0	-	1.0	-	1.0	μs
t _{dis}	disable time	OE to A; no external load	[2]	1.0	11.0	1.0	11.0	1.0	11.0	1.0	11.0	ns
		OE to B; no external load	[2]	1.0	15.4	1.0	13.5	1.0	12.4	1.0	12.1	ns
		OE to A		-	260	-	230	-	230	-	230	ns
		OE to B		-	200	-	200	-	200	-	200	ns

Skew between any two outputs of the same package switching in the same direction.

Table 11. Dynamic characteristics for temperature range -40 °C to +85 °C^[1]...continued

Voltages are referenced to GND (ground = 0 V); for test circuit see <u>Figure 5</u>; for wave forms see <u>Figure 3</u> and <u>Figure 4</u>.

Symbol	Parameter	Conditions					Vcc	C(B)				Unit
				1.8 V ±	0.15 V		5 V .2 V	3.3 V :	± 0.3 V	5.0 V :	± 0.5 V	
				Min	Max	Min	Max	Min	Max	Min	Max	
t _t	transition	A port		0.8	4.1	0.8	4.1	0.8	4.1	0.8	4.1	ns
	time	B port		0.9	4.7	0.6	3.2	0.5	2.5	0.4	2.7	ns
t _{sk(o)}	output skew time	between channels	[3]	-	0.5	-	0.5	-	0.5	-	0.5	ns
t _W	pulse width	data inputs		20	-	17	-	17	-	17	-	ns
f _{data}	data rate			-	49	-	60	-	60	-	60	Mbps
V _{CC(A)} =	2.5 V ± 0.2 V											,
t _{pd}	propagation	A to B		-	-	1.1	6.3	1.0	5.2	0.9	4.7	ns
	delay	B to A		-	-	1.2	6.6	1.1	5.1	0.9	4.4	ns
t _{en}	enable time	OE to A, B		-	-	-	1.0	-	1.0	-	1.0	μs
t _{dis}	disable time	OE to A; no external load	[2]	-	-	1.0	9.2	1.0	9.2	1.0	9.2	ns
		OE to B; no external load	[2]	-	-	1.0	11.9	1.0	10.7	1.0	10.2	ns
		OE to A		-	-	-	200	-	200	-	200	ns
		OE to B		-	-	-	200	-	200	-	200	ns
t _t	transition	A port		-	-	0.7	3.0	0.7	3.0	0.7	3.0	ns
	time	B port		-	-	0.7	3.2	0.5	2.5	0.4	2.7	ns
t _{sk(o)}	output skew time	between channels	[3]	-	-	-	0.5	-	0.5	-	0.5	ns
t _W	pulse width	data inputs		-	-	12	-	10	-	10	-	ns
f _{data}	data rate			-	-	-	85	-	100	-	100	Mbps
V _{CC(A)} =	3.3 V ± 0.3 V											
t _{pd}	propagation	A to B		-	-	-	-	0.9	4.7	0.8	4.0	ns
	delay	B to A		-	-	-	-	1.0	4.9	0.9	3.8	ns
t _{en}	enable time	OE to A, B		-	-	-	-	-	1.0	-	1.0	μs
t _{dis}	disable time	OE to A; no external load	[2]	-	-	-	-	1.0	9.2	1.0	9.2	ns
		OE to B; no external load	[2]	-	-	-	-	1.0	10.1	1.0	9.6	ns
		OE to A		-	-	-	-	-	260	-	260	ns
		OE to B		-	-	-	-	-	200	-	200	ns
t _t	transition	A port		-	-	-	-	0.7	2.5	0.7	2.5	ns
	time	B port		-	-	-	-	0.5	2.5	0.4	2.7	ns
t _{sk(o)}	output skew time	between channels	[3]	-	-	-	-	-	0.5	-	0.5	ns
t _W	pulse width	data inputs		-	-	_	-	10	-	10	-	ns
f _{data}	data rate			-	-	-	-	-	100	-	100	Mbps

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- t_{pd} is the same as t_{PLH} and t_{PHL} ; t_{en} is the same as t_{PZL} and t_{PZH} ; t_{dis} is the same as t_{PLZ} and t_{PHZ} ; t_{t} is the same as t_{THL} and t_{TLH} Delay between OE going LOW and when the outputs are actually disabled.
- Skew between any two outputs of the same package switching in the same direction.

Table 12. Dynamic characteristics for temperature range -40 $^{\circ}$ C to +125 $^{\circ}$ C^[1] Voltages are referenced to GND (ground = 0 V); for test circuit see <u>Figure 5</u>; for wave forms see <u>Figure 3</u> and <u>Figure 4</u>.

Symbol	Parameter	Conditions					Vc	C(B)				Unit
				1.8 V ±	0.15 V		5 V .2 V	3.3 V	± 0.3 V	5.0 V	± 0.5 V	
				Min	Max	Min	Max	Min	Max	Min	Max	
V _{CC(A)} =	1.5 V ± 0.1 V										'	
t _{pd}	propagation	A to B		1.4	15.9	1.2	13.1	1.1	13.0	8.0	12.9	ns
	delay	B to A		0.9	17.2	0.7	15.0	0.4	14.7	0.3	16.7	ns
t _{en}	enable time	OE to A, B		-	1.0	-	1.0	-	1.0	-	1.0	μs
t _{dis}	disable time	OE to A; no external load	[2]	1.0	12.5	1.0	12.5	1.0	12.5	1.0	12.5	ns
		OE to B; no external load	[2]	1.0	18.1	1.0	16.2	1.0	14.9	1.0	14.6	ns
		OE to A		-	340	-	280	-	280	-	300	ns
		OE to B		_	220	_	220	-	220	_	220	ns
t _t	transition	A port		0.9	7.1	0.9	7.1	0.9	7.1	0.9	7.1	ns
	time	B port		0.9	6.5	0.6	5.2	0.5	4.8	0.4	4.7	ns
t _{sk(o)}	output skew time	between channels	[3]	-	0.5	-	0.5	-	0.5	-	0.5	ns
t _W	pulse width	data inputs		25	-	25	-	25	-	25	-	ns
f _{data}	data rate			-	40	-	40	-	40	-	40	Mbps
V _{CC(A)} =	1.8 V ± 0.15 V			I		1				I.		
t _{pd}	propagation	A to B		1.6	14.0	1.4	10.7	1.3	9.8	1.2	9.5	ns
	delay	B to A		1.5	15.0	1.3	11.4	1.0	10.6	0.9	10.1	ns
t _{en}	enable time	OE to A, B		-	1.0	-	1.0	-	1.0	-	1.0	μs
t _{dis}	disable time	OE to A; no external load	[2]	1.0	11.5	1.0	11.5	1.0	11.5	1.0	11.5	ns
		OE to B; no external load	[2]	1.0	16.5	1.0	14.5	1.0	13.3	1.0	12.7	ns
		OE to A		-	280	-	250	-	250	-	250	ns
		OE to B		-	220	-	220	-	220	-	220	ns
t _t	transition	A port		0.8	6.2	0.8	6.1	0.8	6.1	0.8	6.1	ns
	time	B port		0.9	5.8	0.6	5.2	0.5	4.8	0.4	4.7	ns
t _{sk(o)}	output skew time	between channels	[3]	-	0.5	-	0.5	-	0.5	-	0.5	ns
t _W	pulse width	data inputs		22	-	19	-	19	-	19	-	ns
f _{data}	data rate			-	45	-	55	-	55	-	55	Mbps
	2.5 V ± 0.2 V		-	1	1	1	1	1	1	1		

Table 12. Dynamic characteristics for temperature range -40 °C to +125 °C^[1]...continued Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 5; for wave forms see Figure 3 and Figure 4.

Symbol	Parameter	Conditions					Vc	C(B)				Unit
				1.8 V ±	0.15 V		5 V .2 V	3.3 V :	± 0.3 V	5.0 V	± 0.5 V	
				Min	Max	Min	Max	Min	Max	Min	Max	
t _{pd}	propagation	A to B		-	-	1.1	9.3	1.0	8.2	0.9	7.7	ns
	delay	B to A		-	-	1.2	9.6	1.1	8.1	0.9	7.4	ns
t _{en}	enable time	OE to A, B		-	-	-	1.0	-	1.0	-	1.0	μs
t _{dis}	disable time	OE to A; no external load	[2]	-	-	1.0	9.6	1.0	9.6	1.0	9.6	ns
		OE to B; no external load	[2]	-	-	1.0	12.6	1.0	11.4	1.0	10.8	ns
		OE to A		-	-	_	220	-	220	-	220	ns
		OE to B		-	-	-	220	-	220	-	220	ns
t _t	transition	A port		-	-	0.7	5.0	0.7	5.0	0.7	5.0	ns
	time	B port		-	-	0.7	4.6	0.5	4.8	0.4	4.7	ns
t _{sk(o)}	output skew time	between channels	[3]	-	-	-	0.5	-	0.5	-	0.5	ns
t _W	pulse width	data inputs;		-	-	14	-	13	-	10	-	ns
f _{data}	data rate			-	-	-	75	-	80	-	100	Mbps
V _{CC(A)} =	3.3 V ± 0.3 V										'	
t _{pd}	propagation	A to B		-	-	-	-	0.9	7.7	0.8	7.0	ns
	delay	B to A		-	-	-	-	1.0	7.9	0.9	6.8	ns
t _{en}	enable time	OE to A, B		-	-	-	-	-	1.0	-	1.0	μs
t _{dis}	disable time	OE to A; no external load	[2]	-	-	-	-	1.0	9.5	1.0	9.5	ns
		OE to B; no external load	[2]	-	-	-	-	1.0	10.7	1.0	9.6	ns
		OE to A		-	-	-	-	-	280	-	280	ns
		OE to B		-	-	-	-	-	220	-	220	ns
t _t	transition	A port		-	-	_	-	0.7	4.5	0.7	4.5	ns
	time	B port		-	-	_	-	0.5	4.1	0.4	4.7	ns
t _{sk(o)}	output skew time	between channels	[3]	-	-	-	-	-	0.5	-	0.5	ns
t _W	pulse width	data inputs		-	-	-	-	10	-	10	-	ns
f _{data}	data rate			-	-	-	-	-	100	-	100	Mbps

 t_{pd} is the same as t_{PLH} and t_{PHL} ; t_{en} is the same as t_{PZL} and t_{PZH} ; t_{dis} is the same as t_{PLZ} and t_{PHZ} ; t_{t} is the same as t_{THL} and t_{TLH} Delay between OE going LOW and when the outputs are actually disabled. Skew between any two outputs of the same package switching in the same direction.

Table 13. Typical power dissipation capacitance Voltages are referenced to GND (ground = 0 V). [1][2]

Symbol	Parameter	Conditions				V _{CC(A)}				Unit
			1.2 V	1.2 V	1.5 V	1.8 V	2.5 V	2.5 V	3.3 V	
			$V_{CC(B)}$							
			1.8 V	5.0 V	1.8 V	1.8 V	2.5 V	5.0 V	3.3 V to 5.0 V	
T _{amb} = 2	5 °C									
C _{PD}	power	outputs enabled; OE = V _{CC(A)}								
	dissipation capacitance	A port: (direction A to B)	5	5	5	5	5	5	5	pF
	'	A port: (direction B to A)	8	8	8	8	8	8	8	pF
		B port: (direction A to B)	18	18	18	18	18	18	18	pF
		B port: (direction B to A)	13	16	12	12	12	12	13	pF
		outputs disabled; OE = GND								
		A port: (direction A to B)	0.12	0.12	0.04	0.05	0.08	0.08	0.07	pF
		A port: (direction B to A)	0.01	0.01	0.01	0.01	0.01	0.01	0.01	pF
		B port: (direction A to B)	0.01	0.01	0.01	0.01	0.01	0.01	0.01	pF
		B port: (direction B to A)	0.07	0.09	0.07	0.07	0.05	0.09	0.09	pF

[1] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$ where:

 f_i = input frequency in MHz;

f_o = output frequency in MHz;

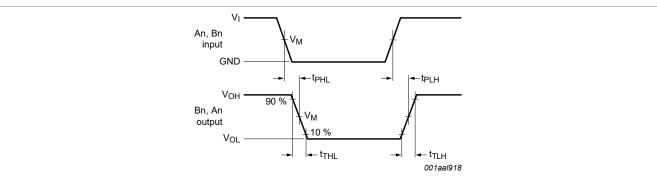
C_L = load capacitance in pF;

V_{CC} = supply voltage in V;

N = number of inputs switching;

 $\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs. f_i = 10 MHz; V_i = GND to V_{CC} ; t_r = t_f = 1 ns; C_L = 0 pF; R_L = ∞ Ω .

11 Waveforms



Measurement points are given in Table 14.

V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

Figure 3. Data input (An, Bn) to data output (Bn, An) propagation delay times

NTB0102-Q100

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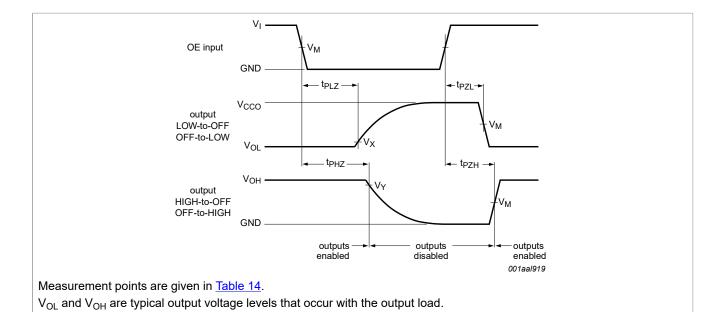
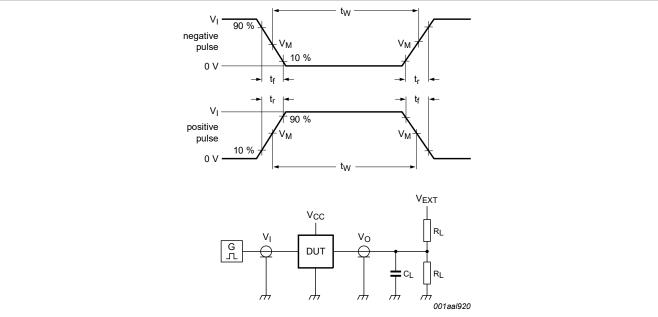


Table 14. Measurement points^[1]

Figure 4. Enable and disable times

Supply voltage	Input	Output		
V _{CCO}	V _M	V _M	V _X	V _Y
1.2 V	0.5V _{CCI}	0.5V _{CCO}	V _{OL} + 0.1 V	V _{OH} - 0.1 V
1.5 V ± 0.1 V	0.5V _{CCI}	0.5V _{CCO}	V _{OL} + 0.1 V	V _{OH} - 0.1 V
1.8 V ± 0.15 V	0.5V _{CCI}	0.5V _{CCO}	V _{OL} + 0.15 V	V _{OH} - 0.15 V
2.5 V ± 0.2 V	0.5V _{CCI}	0.5V _{CCO}	V _{OL} + 0.15 V	V _{OH} - 0.15 V
3.3 V ± 0.3 V	0.5V _{CCI}	0.5V _{CCO}	V _{OL} + 0.3 V	V _{OH} - 0.3 V
5.0 V ± 0.5 V	0.5V _{CCI}	0.5V _{CCO}	V _{OL} + 0.3 V	V _{OH} - 0.3 V

^[1] V_{CCI} is the supply voltage associated with the input and V_{CCO} is the supply voltage associated with the output.



Test data is given in Table 15.

All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz; $Z_O = 50 \Omega$; $dV/dt \geq 1.0 V/$ ns.

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

V_{EXT} = External voltage for measuring switching times.

Figure 5. Test circuit for measuring switching times

Table 15. Test data

Supply voltage	Supply voltage Input			Load		V _{EXT}			
V _{CC(A)}	V _{CC(B)}	V _I ^[1]	Δt/ΔV	C _L	R _L ^[2]	t _{PLH} , t _{PHL}	t _{PZH} , t _{PHZ}	$t_{PZL}, t_{PLZ}^{[3]}$	
1.2 V to 3.6 V	1.65 V to 5.5 V	V_{CCI}	≤ 1.0 ns/V	15 pF	50 kΩ, 1 ΜΩ	open	open	2V _{CCO}	

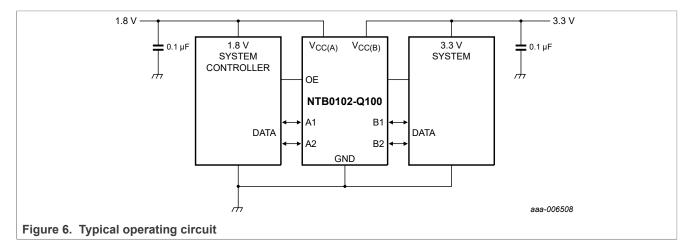
 V_{CCI} is the supply voltage associated with the input. For measuring data rate, pulse width, propagation delay and output rise and fall measurements, R_L = 1 $M\Omega$; for measuring enable and disable times, R_L = [2] 50 kΩ.

 V_{CCO} is the supply voltage associated with the output. [3]

12 Application information

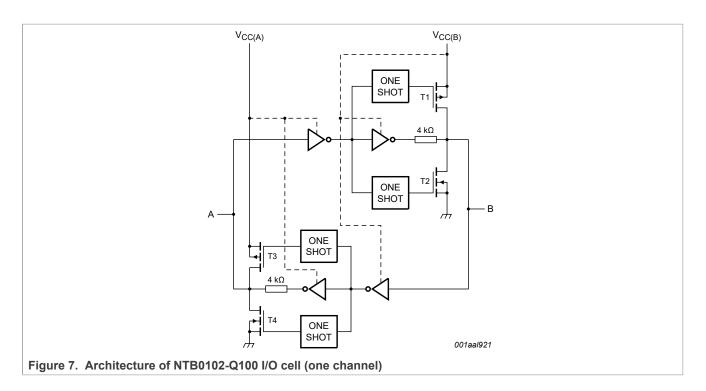
12.1 Applications

Voltage level-translation applications. The NTB0102-Q100 can be used to interface between devices or systems operating at different supply voltages. See <u>Figure 6</u> for a typical operating circuit using the NTB0102-Q100.



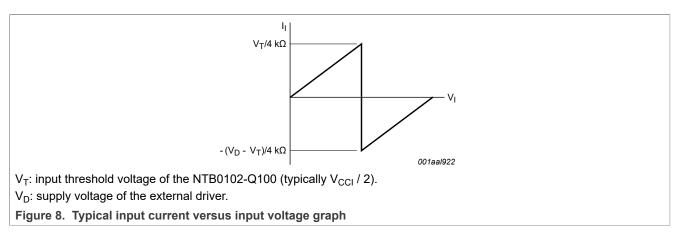
12.2 Architecture

The architecture of the NTB0102-Q100 is shown in Figure 7. The device does not require an extra input signal to control the direction of data flow from A to B or from B to A. In a static state, the output drivers of NTB0102-Q100 can maintain a defined output level, however, the output architecture is designed to be weak. This design enables an external driver to override the drivers when data on the bus starts flowing in the opposite direction. The output of one-shot circuits detect rising or falling edges on the A or B ports. During a rising edge, the one-shot circuits turn on the PMOS transistors (T1, T3) for a short duration, accelerating the LOW-to-HIGH transition. Similarly, during a falling edge, the one-shot circuits turn on the NMOS transistors (T2, T4) for a short duration, accelerating the HIGH-to-LOW transition. During output transitions, the typical output impedance is 70 Ω at $V_{\rm CCO}$ = 1.2 V to 1.8 V, 50 Ω at $V_{\rm CCO}$ = 1.8 V to 3.3 V and 40 Ω at $V_{\rm CCO}$ = 3.3 V to 5.0 V.



12.3 Input driver requirements

For correct operation, the device driving the data I/Os of the NTB0102-Q100 must have a minimum drive capability of ±2 mA See Figure 8 for a plot of typical input current versus input voltage.



12.4 Power-up

During operation $V_{CC(A)}$ must never be higher than $V_{CC(B)}$. However, during power-up, $V_{CC(A)} \ge V_{CC(B)}$ does not damage the device, so either power supply can be ramped up first. There is no special power-up sequencing required. The NTB0102-Q100 includes circuitry that disables all output ports when either $V_{CC(A)}$ or $V_{CC(B)}$ is switched off.

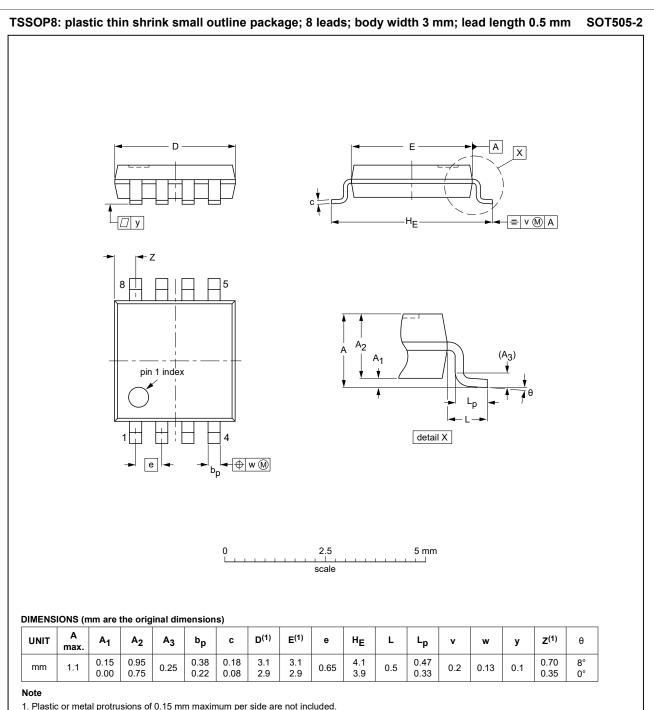
12.5 Enable and disable

An output enable input (OE) is used to disable the device. Setting OE = LOW causes all I/Os to assume the high-impedance OFF-state. The disable time (t_{dis} with no external load) indicates the delay between when OE goes LOW and when outputs actually become disabled. The enable time (t_{en}) indicates the amount of time that must be allowed for one one-shot circuitry to become operational after OE is taken HIGH. To ensure the high-impedance OFF-state during power-up or power-down, pin OE should be tied to GND through a pull-down resistor. The current-sourcing capability of the driver determines the minimum value of the resistor.

12.6 Pull-up or pull-down resistors on I/O lines

As mentioned previously the NTB0102-Q100 is designed with low static drive strength to drive capacitive loads of up to 70 pF. To avoid output contention issues, any pull-up or pull-down resistors used must be above 50 k Ω . For this reason, the NTB0102-Q100 is not recommended for use in open-drain driver applications such as 1-Wire or I²C-bus. For these applications, the NTS0102-Q100 level translator is recommended.

13 Package outline



1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	1920E DATE	
SOT505-2					02-01-16	

Figure 9. Package outline SOT505-2 (TSSOP8)

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14 Abbreviations

Table 16. Abbreviations

Acronym	Description
CDM	Charged Device Model
DUT	Device Under Test
ESD	ElectroStatic Discharge
НВМ	Human Body Model
NMOS	N-type Metal Oxide Semiconductor
PMOS	P-type Metal Oxide Semiconductor
PRR	Pulse Repetition Rate

15 Revision history

Table 17. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes			
NTB0102_Q100 v.2.0	20220420	Product data sheet	-	NTB0102_Q100 v.1.0			
Modifications:	 Removed type number NTB0102GD-Q100 <u>Section 3</u>: Updated look and feel 						
NTB0102_Q100 v.1.0	20130418	Product data sheet	-	-			

16 Legal information

16.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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